Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/645,249	TAKAHASHI ET AL.	
Examiner	Art Unit	
Justin Krause	3682	

SEARCHED				
Class	Subclass	Date	Examiner	
74	473.3 473.12 473.1 473.19 473.21	5/2/2006	JMK	
	473.35			
	484R 552			
200	61.54			
	61.57			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See East history	5/2/2006	JMK		
74 search W Joyce, C Kim				
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